

08/072,206

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

K1/B6g
Jm
2-13-96



the patent application of:

Applicants: Rodney E. Schwartz et al.

Examiner: J. Mancuso

Serial No: 08/072,206

Art Unit: 2613

Filing Date: June 4, 1993

Title: INTEGRATED CIRCUIT PROBE CARD INSPECTION SYSTEM

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Assistant Commissioner for Patents
Washington, D.C. 20231

AMENDMENT AFTER FINAL REJECTION, EXPEDITED HANDLING REQUESTED

RESPONSE TO FINAL OFFICE ACTION DATED OCTOBER 2, 1995

Dear Sir:

Favorable reconsideration of the above-identified application is respectfully requested in view of the amendments and comments presented below.

Filed concurrently herewith is a petition and fee for a one-month extension of time to respond to the Office Action.

AMENDMENTS

In the Claims

Please amend claim 1 as follows:

- 536
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cont
1. (Twice Amended) An integrated circuit probe card inspection system for probes in a probe array, comprising:
a viewing system for providing a digital image of the tip of each probe,